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<b>Substitute for form 1449A/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				Application Number		Filed Herewith	
				Filing Date		January 23, 2002	
				First Named Inventor:		Gary R. Janik	
				Examiner name: unknown		GROUP: unknown	
Sheet	1	of	1	Attorney Docket Number		KLA-003	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initials*	Cited No. <sup>1</sup>	U.S. Patent Document Number      Kind Code <sup>2</sup> (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Info. Appear	
JS	A01	5485091		Verkuil	01/16/1996		
JS	A02	5608526		Piwonka-Corle et al.	03/04/1997		
JS	A03	5747813		Norton et al.	05/05/1998		
JS	A04	6261853	B1	Howell et al.	07/17/2001		
JS	A05	6325078	B2	Kamieniecki	12/04/2001		
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initials*	Cited No. <sup>1</sup>	Foreign Patent Document Office <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Info. Appear	T <sup>6</sup>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	Pending US Patent Application entitled: "System For Analyzing Surface Characteristics With Self-Calibrating Capability", Wang et al.; Serial No. 09/298,007.						
JS	Pending US Patent Application entitled: "Method and Apparatus For Improved X-Ray Reflection Measurement"; Janik et al.; Serial No. 10/005,610 filed 11/07/2001.						
EXAMINER <i>David J. Janik</i>				DATE CONSIDERED 5/11/04			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.